

Test of Basic Gates

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Testing for Single Stuck Line (SSL) Faults

3-input NAND Gate



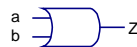
	a/0	a/1	b/0	b/1	c/0	c/1	z/0	z/1
000							X	
001							X	
010							X	
011		X					X	
100							X	
101				X			X	
110						X	X	
111	X		X		X			X

- number of SSLs=4x2=8
- Minimal test set $t=\{011, 101, 110, 111\}$
- Inversions on inputs/outputs do not change the number of tests

EECS579: Digital System Testing
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Testing for SSL



	a/0	a/1	b/0	b/1	z/0	z/1
00		X		X		X
01			X		X	
10	X				X	
11					X	

- number of SSLs = 3x2 = 6
- Minimal test set $t=\{00, 01, 10\}$
- t also tests 2-input nor gate

Test of Basic Gates

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Test Set for AND/NAND; OR/NOR Gates

# of Inputs	Gate Type	Test Set
2	AND/NAND	{00, 10, 11}
3	AND/NAND	{011, 101, 110, 111}
2	OR/NOR	{00, 01, 10}
3	OR/NOR	{00, 100, 010, 001}

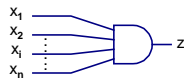
- Theorem 1:** An n-input AND or NAND gate has a unique minimal set of n+1 tests that covers (or detects) all single-stuck-line (SSL) faults:
011...11, 101...11, 110...11, ..., 111...10, 111...11
- Theorem 2:** An n-input OR or NOR gate has a unique minimal set of n+1 tests that covers (or detects) all SLL faults:
100...00, 010...00, 001...00, 000...01, 000...00

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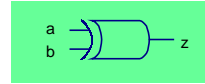
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Test Set for AND/NAND; OR/NOR Gates



- SA1
 - Input line x_i is tested for $x_i/1$ if $x_i=0$
 $\wedge \forall j \neq i, x_j=1$
 - $\{\forall i, x_i/1, z/1\}$ is an equivalent class of faults
 - ⇒ n tests patterns test n+1 SA1 faults corresponding to all inputs and output lines
- SA0: Test vector 11...11 tests z/0 and $\forall i, x_i/0$
 - ⇒ The test vector 11...11 tests n+1 SA0 faults
- Minimal test set required to test 2(n+1) SSL faults is n+1

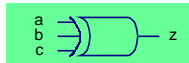
Test Set for XOR/XNOR Gates



	a/0	a/1	b/0	b/1	z/0	z/1
00		X		X	X	
01		X	X			X
10	X			X	X	
11	X		X			X

- No essential test vector
- At least 3 tests needed to cover all faults
- Minimal complete tests: $T_1=\{00, 01, 10\}$; $T_2=\{00, 01, 11\}$; $T_3=\{00, 10, 11\}$
- Every input pattern detects an SSL fault on every line of the gate

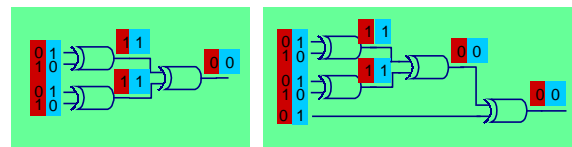
Test Set for XOR/XNOR Gates



	a/0	a/1	b/0	b/1	c/0	c/1	z/0	z/1
000	X			X		X	X	
001	X			X	X			X
010		X	X			X	X	
011		X	X		X			X
100	X		X		X	X		
101	X		X	X			X	
110	X		X		X	X		
111	X		X		X	X	X	

- No essential test vector
- Any 2 complementary input patterns form a complete test set
- Example: (000, 111) or (010, 101)

Tests for Parity Circuit



- General n-input XOR gate ($z=1$ iff total # of 1's is odd)
- If $n=2m+1$ (odd), then any two complementary input patterns (X, X') detect all SSL faults in an XOR or XNOR gate
- If $n=2m$ (even), then any (X, X') detect all SSL faults affecting input lines, but only one fault z/d [$d=0, 1$], on the output line. A third test to detect z/d is needed.